What are the Proper Transport Models at the Nanoscale?

Semiclassical Transport Approaches Quantum Transport Atomistic Simulations







COMPUTE

Advantages and disadvantages of models

Range of Validity of Different Methods

	$L \ll l_{e-ph}$			$L \sim l_{e-ph}$	$L >> l_{e-ph}$
	$L < \lambda$	$L < l_{e-e}$	$L >> l_{e-e}$		
Transport Regime	Quantum	Ballistic	Fluid	Fluid	Diffusive
Scattering	Rare	Rare	e-e (Many), e-p	h (Few)	Many
Model:					
Drift-Diffusion					
Hydrodynamic	Quantum Hydrodynamic				
Monte Carlo					
Schrodinger/Green's					
Functions	Wave				
Applications	Nanowires,	Ballistic			
	Superlattices	Transistor	Current IC's	Current IC's	Older IC's

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COMPUTE

Boltzmann Transport Equation

• In its most general form, the BTE equals to:

$$\begin{split} &\frac{\partial f}{\partial t} + \vec{v} \cdot \nabla_r f + (-e)\vec{\varepsilon} \cdot \nabla_p f = \frac{\partial f}{\partial t}|_{coll} = \\ &= \sum_{i=1}^N \sum_{\vec{p}'} \left[S_i(\vec{p}', \vec{p}) f(\vec{r}, \vec{p}', t) - S_i(\vec{p}, \vec{p}') f(\vec{r}, \vec{p}, t) \right] \end{split}$$

• The collision integral on the RHS can be expressed as:

$$RHS = \sum_{\vec{p}'} \sum_{i=1}^{N} [S_i(\vec{p}', \vec{p}) f(\vec{r}, \vec{p}', t)] - f(\vec{r}, \vec{p}, t) \sum_{\vec{p}'} \sum_{i=1}^{N} S_i(\vec{p}, \vec{p}')$$

D. K. Ferry, "Semiconductors" (Macmillan, New York, 1991).

Path Integral Solution of the BTE

 The path integral solution of the Boltzmann Transport Equation (BTE), where L=N∆t and t_n=n∆t, is of the form:

$$f_{N}(t) = \Delta t \sum_{m=0}^{N-1} f_{m}(p') S_{eff}(p', p + eE(N-m)\Delta t) e^{-\Gamma(N-m)\Delta t}$$
$$g_{m}(p + eE(N-m)\Delta t)$$

K. K. Thornber and Richard P. Feynman, Phys. Rev. B 1, 4099 (1970).



Rees, H. D., 1969, J. Phys. Chem. Solids 30, 643.

Path Integral Solution of the BTE

- Using path integral formulation to the BTE we have shown that one can decompose the solution procedure into two components:
 - **Carrier free-flights** that are interrupted by scattering events

$$\mathbf{k}(t) = \mathbf{k}(0) - \boldsymbol{e}(\mathbf{v} \times \mathbf{B} + \mathbf{E})t/\hbar$$

• **Memory-less scattering events** that change the momentum and the energy of the particle instantaneously

Ways of solving the BTE

- Single particle Monte Carlo Technique
 - Follow single particle for long enough time to collect sufficient statistics
 - Practical for characterization of bulk materials or inversion layers
- Ensemble Monte Carlo Technique
 - MUST BE USED when modeling SEMICONDUCTOR DEVICES to have the complete self-consistency built in

Carlo Jacoboni and Lino Reggiani, The Monte Carlo method for the solution of charge transport in semiconductors with applications to covalent materials, Rev. Mod. Phys. 55, 645 - 705 (1983).







E. Pop, R. W. Dutton and K. E. Goodson, JOURNAL OF APPLIED PHYSICS VOLUME 96, NUMBER 9 1 NOVEMBER 2004

Particle Based Device Simulators

INCORPORATION OF THE SHORT-RANGE COULOMB INTERACTION



Real-Space Approach

- Requires 3D device simulator, otherwise the method fails
- There are several variants of this method
 - Corrected Coulomb approach developed by Vasileska and Gross
 - Particle-particle-mesh (p3m) method by Hockney and Eastwood
 - Fast Multipole method
- Corrected Coulomb approach and p3m method are almost equivalent in philosophy, FMM is very different
- Treatment of the short-range Coulomb interactions using any of these three methods accounts for:
 - Binary collisions + plasma (collective) excitations
 - Screening of the Coulomb interactions
 - Scattering from multiple impurities at the same time which is very important at high substrate doping densities

Simulation Methodologies

Method Complexity

P ³ M	FMM
O(N+MlogM)	O(N)
3	

N=Number of particles

M=Number of Mesh Points

Computation time

Machine: P-4 , 2GHz Mesh points: 64X24X24 Particles: 690

Time for each iteration		
P ³ M	FMM	
~24 sec	<1sec	





W. J. Gross, D. Vasileska and D. K. Ferry, "IEEE Electron Device Lett. 20, No. 9, pp.463-465 (1999).



W. J. Gross, D. Vasileska and D. K. Ferry, "VLSI Design, Vol. 10, pp. 437-452 (2000).

Corrected Coulomb Approach – Cont'd

- Doping of the N⁺- regions: $N_D^+ = 10^{19} \text{ cm}^{-3}$.
- Mesh: uniform mesh spacing in all directions equal to 10 nm.
- Cases considered:
 - Mesh force only
 - Mesh force + short-range *e* - *e* and *e* - *i* interaction terms





- The mesh force only does not give the correct doping dependence of the low-field electron mobility.
- The inclusion of the **short-range interaction terms** gives simulation low-field mobility data in agreement with experimental values.



Roger W. Hockney, James W. Eastwood, Computer Simulation Using Particles, Taylor & Francis.

P3M Approach – Cont'd Smoothing of the total interparticle force between the long-and shortrange domains can be thought of as ascribing a finite size to particle *i*. A sphere with uniformly decreasing density profile, S(r) is a good choice for smoothing in three dimensions. $\mathbf{S}(\mathbf{r}) = \begin{cases} \frac{48}{\pi r_{sr}^{4}} \left(\frac{r_{sr}}{2} - r\right), & r \leq r_{sr}/2\\ 0, & otherwise \end{cases}$ $\begin{cases} R_{ij}(r) = \frac{q_i q_j}{4\pi\varepsilon} \times \frac{1}{35r_{sr}^2} (224\xi - 224\xi^3 + 70\xi^4 + 48\xi^5 - 21\xi^6) & \xi = \frac{2r}{r_{sr}} \text{ and } 0 \le r \le r_{sr}/2 \\ R_{ij}(r) = \frac{q_i q_j}{4\pi\varepsilon} \times \frac{1}{35r_{sr}^2} (\frac{12}{\xi^2} - 224 + 896\xi - 840\xi^2 + 224\xi^3 + 70\xi^4 - 48\xi^5 + 7\xi^6) & r_{sr}/2 \le r \le r_{sr} \\ R_{ij}(r) = \frac{q_i q_j}{4\pi\varepsilon} \times \frac{1}{s^2} & r \le r_{sr} \end{cases}$

FMM Approach

- Introduced by Rokhlin & Greengard in 1987.
- Called one of the 10 most significant advances in computing of the 20th century.
- For a given precision ε, the FMM achieves the evaluation in O(M+N) operations.
- Edelman: "FMM is all about adding functions".

V. Rokhlin and L. Greengard, J. Comp. Phys., Vol. 73, pp. 325-348, 1987. Sources Points Sources L groups Points Sources L groups Points Sources L groups Points Source Data Hierarchy

Idea of a Single Level FMM

SLEMM

Standard algorithm

• Consider the following binary tree structure induced by a uniform subdivision of the unit interval:



L. Greengard and V. Rokhlin. On the Efficient Implementation of the Fast Multipole Algorithm. Department of Computer Science Research Report 602, Yale University (1988).





Resistor Simulations

Resistor Simulation:



Method	Time/iteration
P ³ M	39 sec
FMM	17 sec

No. of monopole charges: ~22000 Mesh: 40 x 25 x 25

- > Uniform mesh (40 x 25 x 25)
- > An external field of 1kV/cm was applied to ensure linear region of operation.
- The drift velocity was averaged over 5ps with an interval time of 0.1 ps. The first 1.5 ps data were discarded.

H.R. Khan, D. Vasileska, S.S. Ahmed, C. Ringhofer and C. Heitzinger, Journal of Computational Electronics, Vol. 3, Nos. 3-4, pp. 337-340 (2005).



ASU (Vasileska) Model for Self-Heating Effects

$$\begin{pmatrix} \frac{\partial}{\partial t} + v_e(k) \cdot \nabla_r + \frac{e}{\hbar} E(r) \cdot \nabla_k \end{pmatrix} f = \sum_q \left\{ W_{e,q}^{k+q \to k} + W_{a,-q}^{k+q \to k} - W_{e,-q}^{k \to k+q} - W_{a,q}^{k \to k+q} \right\}$$

$$\begin{pmatrix} \frac{\partial}{\partial t} + v_p(q) \cdot \nabla_r \end{pmatrix} g = \sum_k \left\{ W_{e,q}^{k+q \to k} - W_{a,q}^{k \to k+q} \right\} + \left(\frac{\partial g}{\partial t} \right)_{p-p}$$

J. Lai and A. Majumdar, "Concurent thermal and electrical modeling of submicrometer silicon devices", J. Appl. Phys., Vol. 79, 7353 (1996).

$$\begin{split} C_{LO} \, \frac{\partial T_{LO}}{\partial t} &= \frac{3nk_B}{2} \left(\frac{T_e - T_L}{\tau_{e-LO}} \right) + \frac{nm^* v_d^2}{2\tau_{e-LO}} - C_{LO} \left(\frac{T_{LO} - T_A}{\tau_{LO-A}} \right), \\ C_A \, \frac{\partial T_A}{\partial t} &= \nabla \cdot \left(k_A \nabla T_A \right) + C_{LO} \left(\frac{T_{LO} - T_A}{\tau_{LO-A}} \right) + \frac{3nk_B}{2} \left(\frac{T_e - T_L}{\tau_{e-L}} \right). \end{split}$$

K. Raleva, D. Vasileska, S. M. Goodnick and M. Nedjalkov, IEEE Transactions on Electron Devices, vol. 55, issue 6, pp. 1306-1316, June 2008.





Ashegi, Leung, Wong, Goodson, Appl. Phys. Lett. 71, 1798 (1997)

Particle-Based Device Simulators

INCORPORATION OF SPIN

Spin-Orbit Effects

- Rashba SO-coupling
- Generating spin polarized currents in nanowires and constrictions
- Band structure in 2DEG
- Transverse Electron Focalization (TEF) in systems with SOcoupling
- >Spin accumulation (Spin Hall Effect in ballistic mesoscopic systems)

Heterostructures:

The atomistic effect:

$$M = -\frac{eg}{2mc}S \qquad H = -M \cdot B \qquad B = \frac{1}{c}v \times E$$
$$H = \frac{eg}{2mc}S \cdot B = -\frac{eg}{2mc^2}S \cdot v \times E = \frac{eg}{2m^2c^2}S \cdot p \times \nabla\phi(r) \frac{1}{2}$$
The Thomas precession effect



The SO-coupling preserves the time reversal symmetry



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Vasileska + S.M. Goodnick + G. Klimeck

COMPUTE

What do we cover in this section?

- Quantum Transport
 - Solution of the Schrodinger Equation Using Usuki Method
 - Green's Functions
 - Recursive Green's Function Approach
 - Contact Block Reduction Method and its applications



Transfer Matrix Approach on the Example of RTD























An aside – how the Peierl's substitution appears in a tight-binding Hamiltonian

 $\mathbf{k} \to -i\boldsymbol{\nabla} - e\mathbf{A}/\hbar, \qquad \Psi \to \Psi \exp\left(-i\,2\pi\mathbf{A}\cdot\mathbf{r}/\phi_0\right),$



Solving the eigenvalue problem: $\mathbf{T}_{1} \begin{vmatrix} \vec{\psi}_{1} \\ \vec{\psi}_{0} \end{vmatrix} = \lambda \begin{vmatrix} \vec{\psi}_{1} \\ \vec{\psi}_{0} \end{vmatrix}$ yields the modes on the left side of the system Mode eigenvectors have the generic form: $\begin{bmatrix} \vec{u}_m(\pm) \\ \lambda_{-}(\pm)\vec{u}_{-}(\pm) \end{bmatrix}$ \leftarrow redundant There will be M modes that propagates to the right (+) with eigenvalues: propagating $\lambda_m(+) = e^{ik_m a}, m = 1, \cdots, q$ $\lambda_m(+) = e^{-\kappa_m a}, m = q + 1, \cdots, M$ evanescent There will be M modes that propagates to the left (+) with eigenvalues: $\lambda_m(-) = e^{-ik_m a}, m = 1, \cdots, q$ propagating evanescent $\lambda_m(-) = e^{\kappa_m a}, m = q + 1, \cdots, M$ defining $\mathbf{U}_{\pm} = \begin{bmatrix} \vec{u}_1(\pm) & \cdots & \vec{u}_m(\pm) \end{bmatrix}$ and $\lambda_{\pm} = diag \begin{bmatrix} \lambda_1(\pm) & \cdots & \lambda_m(\pm) \end{bmatrix}$ **Complete matrix of eigenvectors:** $\mathbf{U}_{tot} = \begin{vmatrix} \mathbf{U}_{+} & \mathbf{U}_{-} \\ \lambda_{\cdot} \mathbf{U}_{\cdot} & \lambda_{\cdot} \mathbf{U}_{-} \end{vmatrix}$





Final transmission matrix for entire structure is given by

$$\mathbf{t} = - \left(\mathbf{U}^+ \boldsymbol{\lambda}^+\right)^{-1} \left[\mathbf{C}_1^{N+1} - \mathbf{U}^+ \left(\mathbf{U}^+ \boldsymbol{\lambda}^+\right)^{-1}\right]^{-1}$$

A similar iteration gives the reflection matrix

After the transmission problem has been solved, the wave function can be reconstructed

It can be shown that:

$$\mathbf{P}_{N2} = \mathbf{\Psi}_N = \begin{bmatrix} \vec{\psi}_{N,1} & \cdots & \vec{\psi}_{N,k} & \cdots & \vec{\psi}_{N,M} \end{bmatrix}$$

wave function on column N resulting from the kth mode

One can then iterate <u>backwards</u> through the structure: $\Psi_i = \mathbf{P}_{i1} + \mathbf{P}_{i2}\Psi_{i+1}$

The electron density at each point is then given by:

$$n(x, y) = n(i, j) = \sum_{k=1}^{q} |\psi_{ijk}|^2$$





Example – Quantum Dot Conductance as a Function of Gate voltage



Simulation gives comparable 2D electron density to that measured experimentally

$$N = \frac{\hbar^2}{2m^*} (E_F^{3D} - E_0) \sim 4 \times 10^{11} \ cm^{-2}$$

Potential felt by 2DEG- maximum of electron distribution ~7nm below interface



Potential evolves smoothly- calculate a few as a function of V_g , and create the rest by interpolation



Subtracting out a background that removes the underlying steps you get periodic fluctuations as a function of gate voltage. <u>Theory and experiment agree very well</u>



Same simulations also reveal that certain scars may **RECUR** as gate voltage is varied. The resulting periodicity agrees **WELL** with that of the conductance oscillations

* Persistence of the scarring at zero magnetic field indicates its **INTRINSIC** nature

⇒ The scarring is **NOT** induced by the application of the magnetic field

Quantum Transport

RECURSIVE GREEN'S FUNCTIONS APPROACH



Tight-Binding Hamiltonian

- Divide the whole 1D device structure into points which interact with neighboring points through a coupling constant.
- In the **tight-binding method** one can take the basis functions to be any set of localized functions such as atomic *s* and *p*-orbitals, Wannier functions, and so forth.
- A common approximation used to describe the Hamiltonian of layered structures consists of non-vanishing interactions only between nearest neighbor layers. That is, each layer *i* interacts only with itself and its nearest neighbor layers *i*-1 and *i*+1.
- Then, the single particle Hamiltonian of the layered structure is a block tri-diagonal matrix, where diagonal blocks represent the Hamiltonian of layer *i* and off-diagonal blocks represent interactions between layers *i* and *i*+1:





K. B. Kahen, Recursive-Green's-function analysis of wave propagation in two-dimensional nonhomogeneous media, .Phys. Rev. E 47, 2927 - 2933 (1993).





Recursive Green's Function Method at Work

Left-connected Green's function:

Right-connected Green's function:

$$\underline{A}_{1,1} \underline{g}_{1,1}^{Lr} = \underline{I}_{1,1} \quad \underline{A} = \begin{bmatrix} E\underline{I} - \underline{H} - \underline{\Sigma}^{r} \end{bmatrix}$$

$$\underline{g}_{q+1,q+1}^{Lr} = \left(\underline{A}_{q+1,q+1} - \underline{A}_{q+1,q} \underline{g}_{q,q}^{Lr} \underline{A}_{q,q+1}\right)^{-1}$$

$$\underline{A}_{N,N} \underline{g}_{N,N}^{Rr} = \underline{I}_{N,N}$$

$$\underline{g}_{q-1,q-1}^{Rr} = \left(\underline{A}_{q-1,q-1} - \underline{A}_{q-1,q} \underline{g}_{q,q}^{Rr} \underline{A}_{q,q-1}\right)^{-1}$$

$$C_{n}^{r} = \alpha^{Lr} + \alpha^{Lr} \left(\underline{A}_{n} - C_{n}^{r} - \underline{A}_{n}\right)^{-1}$$

Green's functions needed for transmission coefficient and electron density calculations

$$\underline{G}_{q,q}^{r} = \underline{g}_{q,q}^{Lr} + \underline{g}_{q,q}^{Lr} \left(\underline{A}_{q,q+1} \underline{G}_{q+1,q+1}^{r} \underline{A}_{q+1,q}\right) \underline{g}_{q,q}^{Lr}$$
$$\underline{G}_{q+1,q+1}^{r} = \underline{g}_{q+1,q+1}^{Rr} + \underline{g}_{q+1,q+1}^{Rr} \left(\underline{A}_{q+1,q} \underline{G}_{q,q}^{r} \underline{A}_{q,q+1}\right) \underline{g}_{q,q}^{Rr}$$



G. Klimeck, private communication..



Simulation result for formation of inversion channel (electron density) and attainment of threshold voltage (IV) in a nanowire MOSFET. Note that the threshold voltage for this device lies around 0.45V

Quantum Transport

CONTACT BLOCK REDUCTION METHOD









Complexity of CBR vs. Other Algorithms

Method	Computational cost
Transfer matrix + QTBM	$N_E imes O\left(N_{TOTAL}^3 ight)$
NanoMOS (Purdue University)	$\left N_{E} \times N_{x} \times O\left(\left[N_{y} N_{z} \right]^{2} \right) \approx N_{E} \times O\left(N_{TOTAL}^{\frac{5}{3}} \right) \right $
QDAME (IBM, S. Laux)	$N_{TOTAL} imes O\left(N_{eigen}^2 ight) + N_E imes O\left(N_{TOTAL}^{3/2} ight)$
CBR	$N_{TOTAL} \times O\left(N_{eigen}^{2}\right) + N_{E} \times O\left(N_{TOTAL}\right)$
Notations	
N_E : number of energy steps;	
N_{TOTAL} : number of grid points	CBR WINS !!!
N_{eigen} : number of eigenvalues	

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A. Vasileska + S.M. Goodnick + G. Klimeck CRC Press.

COMPUTE



Self-Consistent Tight Binding Calculations

[A. Di Carlo et. al., Solid State Comm. 98, 803 (1996); APL 74, 2002 (1999)]

The electron and hole densities in each 2D layer are given by:



$$n(z) = \frac{1}{(2\pi)^2} \int_{BZ_{//}} d^2 \mathbf{k}_{//} \sum_{c} \left| \left\langle z \left| E_c \mathbf{k}_{//} \right\rangle \right|^2 f(E_c - F_n) \right|$$
$$p(z) = \frac{1}{(2\pi)^2} \int_{BZ_{//}} d^2 \mathbf{k}_{//} \sum_{v} \left| \left\langle z \left| E_v \mathbf{k}_{//} \right\rangle \right|^2 (1 - f(F_h - E_v)) \right|$$

The influence of free carrier charge redistribution and macroscopic polarization fields are included by solving the *Poisson equation:*

$$\frac{d}{dz}D(z) = \frac{d}{dz}\left(-\varepsilon\frac{d}{dz}V_{H}+P\right) = e\left(p-n+N_{D}^{+}-N_{A}^{-}\right) + \frac{boundary}{conditions}$$
$$H = H_{C} + V_{H} \square \left|E_{i}\mathbf{k}_{H}\right| \right)$$

A. Di Carlo, Private Communication.



Conclusions

- Nanoelectronics has revolutionized in many ways our every day life.
- It has made significant impact in fields like medicine in terms of diagnostics and surgical interventions.
- There are many alternative paths and ways in which future nanoelectronics research might go.
- Atomistic simulations will definitely be of crucial importance and need for understanding future nanoelectronic devices
- Parallel computing will be essential for performing multimillion atomistic simulations.